

Session Program

10-12 Nov 2008

13th RD50 Workshop

***Pad Detector Characterization and Defect
Engineering***

CERN, 40-S2-D01

Tuesday 11 November

09:00

Pad Detector Characterization and Defect Engineering

Session | Location: CERN, 40-S2-D01

09:00-09:20 **Annealing studies of mixed irradiated MICRON diodes**

Speaker

Gregor Kramberger

09:20-09:40 **TCT measurements on MCz**

Speaker

Katharina Kaska

09:40-10:00

Charge collection and trapping effects in 75 μm , 100 μm and 150 μm thick n-type epitaxial silicon diodes after proton irradiation

Speaker

Jörn Lange

10:00-10:30 **Discussion: Pad Detector Characterization and Defect Engineering**

10:30-11:00 **Coffee Break**

11:00